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Vladimir Segal et al.FILING DATE  
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## U.S. PATENT DOCUMENTS

Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
AW	AA	5,590,389	12/96	Dunlop et al.			
AW	AB	5,513,512	05/96	Segal			
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						

## FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
AW	AM	WO 98/24945	6/11/98	PCT				
AW	AN	WO 01/29279 A1	4/26/01	PCT				
AW	AO	07286268	10/31/95	Japan (abstract only)				
	AP							
	AQ							

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

AW	AR		Haupt et al., "Drift in film thickness uniformity arising from sputtering target recrystallization". J. Vac. Sci. Technol. A 7(3), May/Jun 1989, pp. 2355-2358.
AW	AS		Ferrasse et al., "Development of a submicrometer-grained microstructure in aluminum 6061 using equal channel angular extrusion". J. Mater. Res. Vol. 12, No. 5, May 1997, pp. 1253-1261.
	AT		

EXAMINER

*AW*

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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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